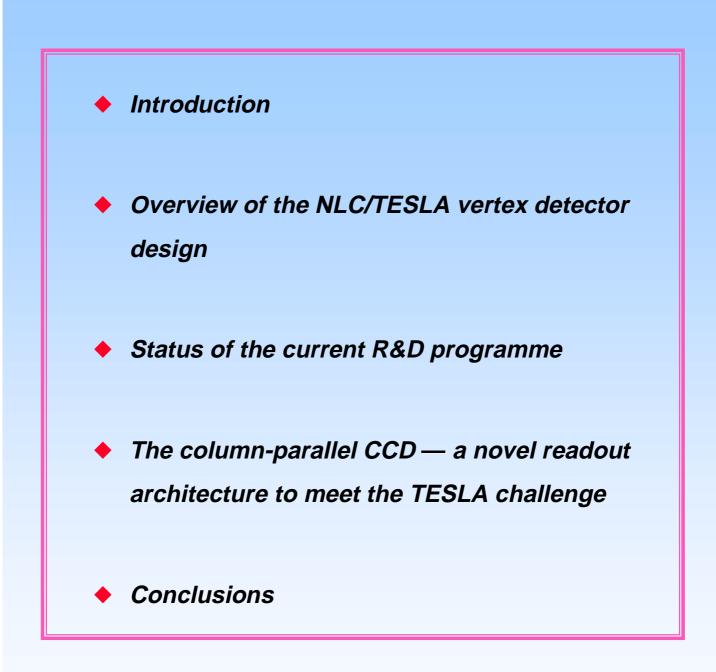
A Fast CCD Vertex Detector for the Future e⁺e⁻ Linear Collider: Some Recent Developments

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on behalf of The LCFI Collaboration

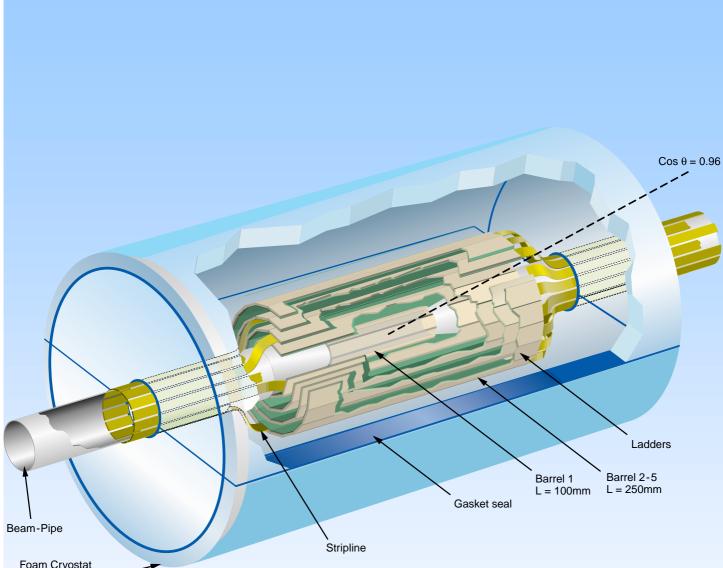
Outline



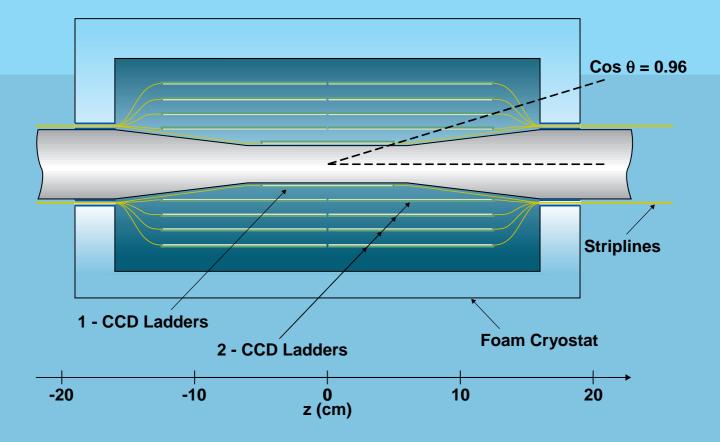
Introduction

- CCDs are ideal candidates for vertex detectors in the linear collider environment
- In SLD they have already demonstrated (with 1990s technology):
 - Excellent 2-d space-point resolution ~3.5μm
 - Very small layer thickness (0.4% X₀ in SLD) → low multiple scattering
 - Serial readout multiplexes data by 200,000:1 → negligible signal cable plant
 - Si-processing technology is still advancing rapidly:
 - ◆ → Faster clocking
 - $\bullet \rightarrow$ Improved signal/noise performance
 - → Larger area devices
- A conceptual design for a CCD-based VXD for the future linear collider has already been presented

CCD VXD for the Future Linear Collider



Foam Cryostat and Faraday Cage



Detector performance targets						
 5-barrel construction to provide redundant stand- alone tracking 						
Inner barrel (B1): radius 15 mm — length 100 mm						
• 3-hit acceptance (including B1) to $\cos \Theta = 0.96$						
 Individual layer thickness 0.06% X₀ 						
Dimensions of largest CCD 125 x 22 mm ²						
Pixel readout rate 50 MHz						
 Neutron radiation tolerance 10¹⁰ n cm⁻² (1 MeV-equivalent) 						

Current R&D programme

Initially (first 3 years) focussed on 3 main areas:

High-speed CCD clocking — up to 50 MHz

Techniques for low-mass ladder assemblies

Neutron irradiation studies

At a later stage:

 Real-time signal processing (min-l clusterfinding) using fast FPGA-based algorithms

Customised CCD design:

column-parallel architectures

two-phase gate structures

Iow-noise output circuitry

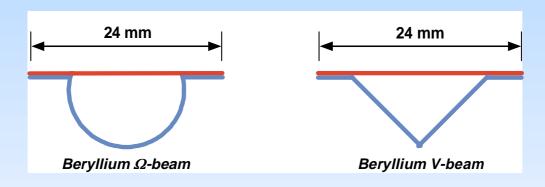
Electronic system design:

clocking and signal processing electronics integrated with CCDs

Mechanical studies

Minimal layer thickness is crucial for precision vertexing (multiple scattering)

Early studies assumed thin CCDs mounted on one side only of a thin Be substrate strengthened by Ω or V beam technique (total thickness ~250 µm):

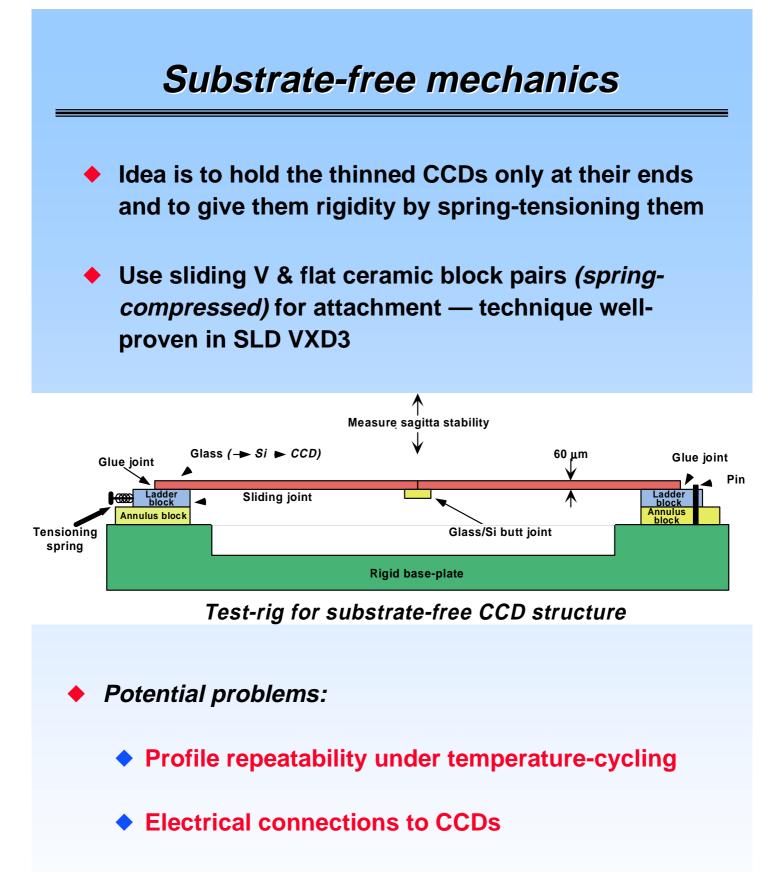


 The CCDs would be thinned to the edge of the epitaxial layer by lapping and etching — ~30 μm

This would give ~0.12% X₀ per layer — of which the Be and associated adhesive contributes 0.09% X₀

Could the Be support structure be eliminated?

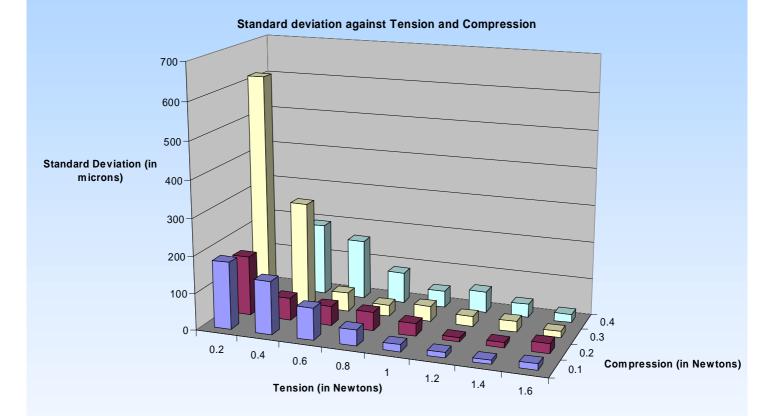
• We are investigating an unsupported-Si technique



- Back-face metallisation for ground-plane difficult
- Handling!

S/S-free mechanics — initial results ...

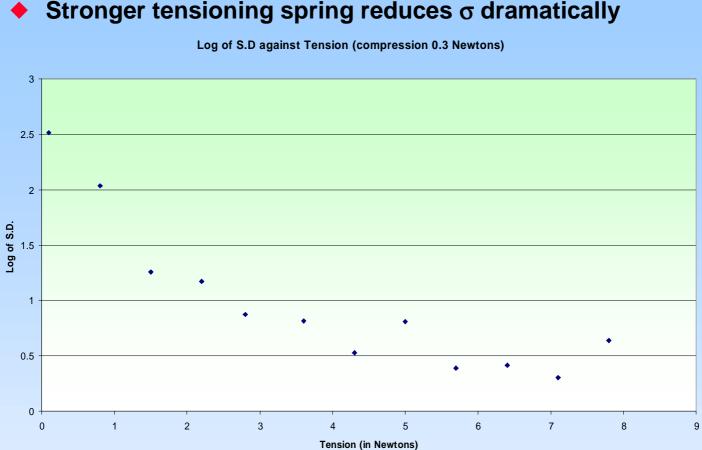
 Sagitta value measured 20 times for each combination of spring compression and tension, physically disturbing system between measurements



Comments:

• Tensioning spring too weak $\rightarrow \sigma$ ~few tens of μm

S/S-free mechanics — initial results ...



Stronger tensioning spring reduces σ dramatically

(Tentative) conclusions:

- The technique appears to work $\sigma \rightarrow$ ~3 μm for spring tension >5 N
- The annulus blocks could be made from better surface-finish ceramic

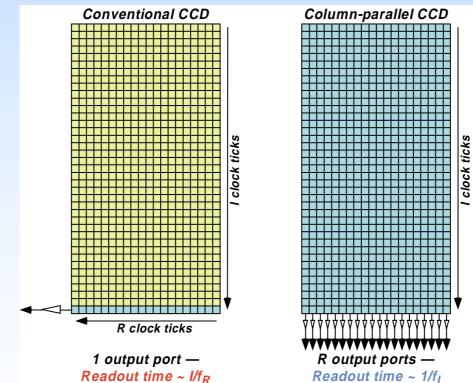
More studies are needed, particularly at low-T ...

Further idea — could the Be beam-pipe thickness be reduced locally ... to 250 µm?

use VXD support shell for strain relief

Column-parallel CCD architecture

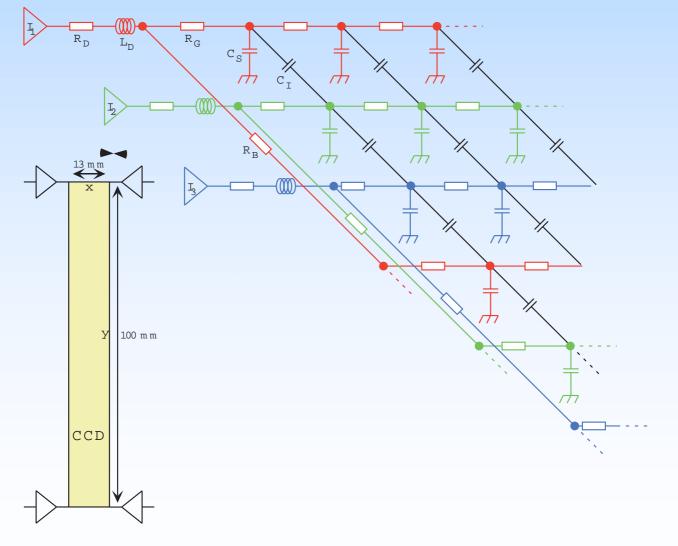
- In X-band LC, B1 CCDs (*r* = 12 mm) must be fully read out between bunch trains (8.3 mS) → 50 MHz clocking
- ◆ 100 bunches/train generates ~10 hits/mm² per CCD from e⁺e⁻ pair background (3T field) → ~0.4% pixel occupancy
- In TESLA, read-out *between* bunch trains would integrate ~2800 bunches → ~20% pixel occupancy
- Solution increase *effective* clocking rate to >1 GHz by eliminating CCD serial (R) register and read out *during* bunch train



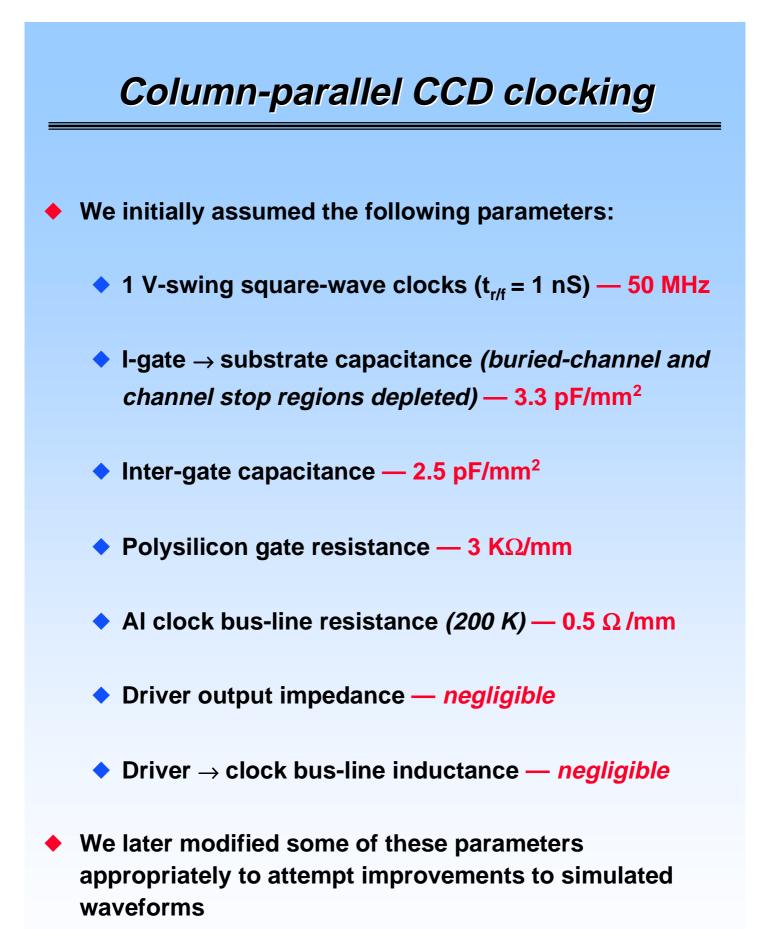
 Consider area CCD as many linear CCDs reading out in parallel → 50 MHz I clock rate for ~1% pixel occupancy

This provides a few interesting technical challenges ...

- Can the CCD I-gates be clocked at 50 MHz with good drive waveforms across entire imaging area — essential for good charge transfer efficiency?
- Is the resultant in-cryostat power dissipation too high to be managed with modest cold gas flow rates?
- We have modelled a realistic inner-layer CCD with SPICE, using Marconi-approved parameters:

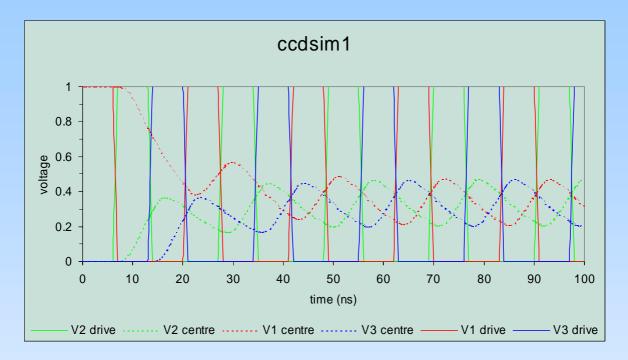


SPICE model of column-parallel CCD gate structure (VXD layer 1 dimensions)

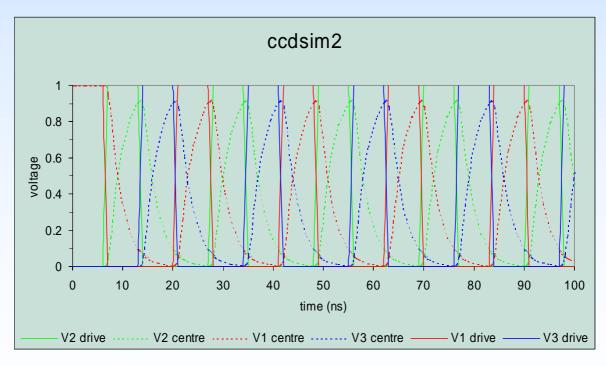


 Starting with these nominal parameters we monitor waveforms at extreme points on the gate structure

a) Drive waveform variation across the CCD in X:

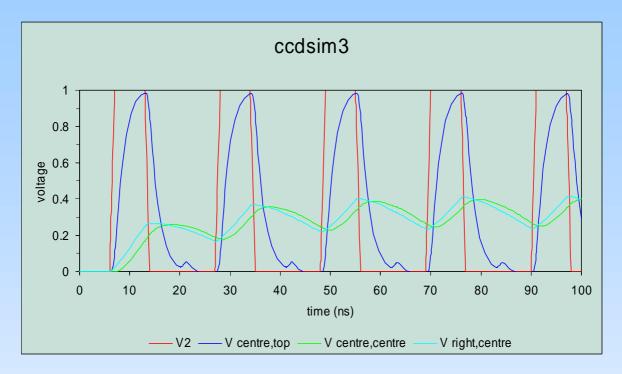


Add 3 μm wide Al overlay to the polysilicon gates —

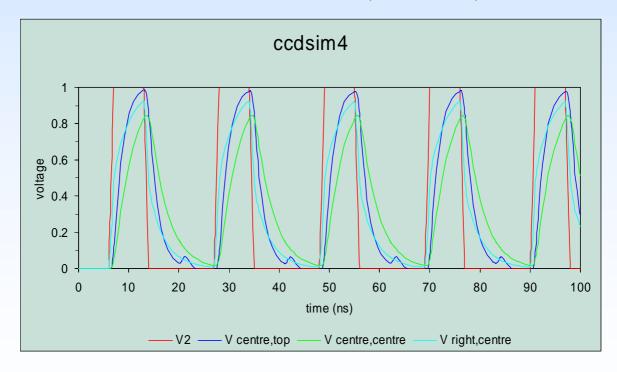


Waveform amplitudes attenuated by <10% in centre (X)</p>

b) Drive waveform variation along the CCD in Y:

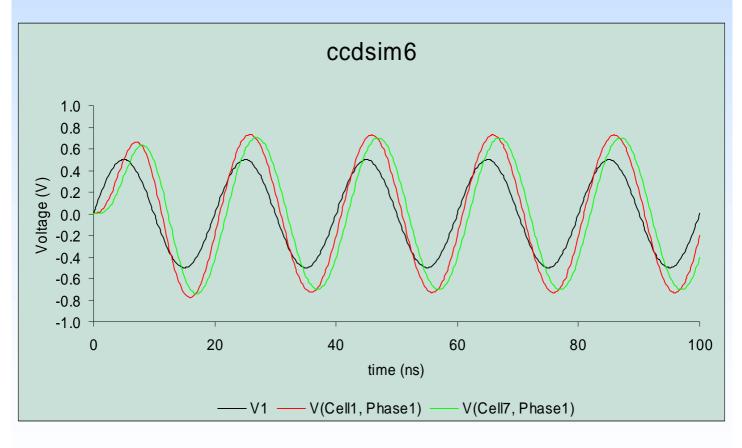


Thicken the AI bus-lines from 1 μ m \rightarrow 10 μ m —



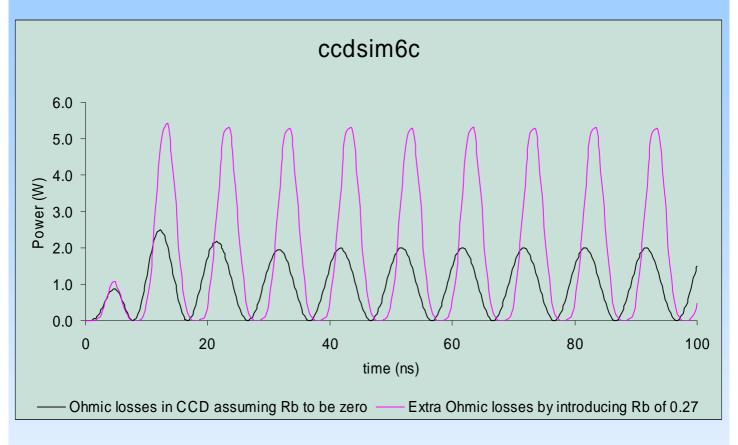
Waveform amplitudes attenuated by <15% in centre (Y)</p>

- c) Move to a 2-phase gate structure with sinusoidal drive waveforms (scale all parameters accordingly and add inductance in the clock driver connection):
- Advantages:
 - Lowest possible driver frequency spectrum
 - Reduced peak current demands on drivers
 - Balanced anti-phase drive waveforms should produce minimal crosstalk to CCD output signals



Waveforms in centre (X) of CCD have ~1.5% attenuation with ~1 nS phase lag

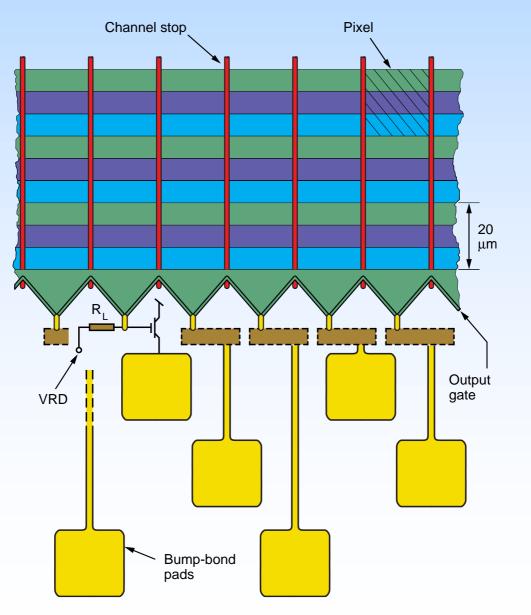
d) Clocking power dissipation (resistive) per CCD:



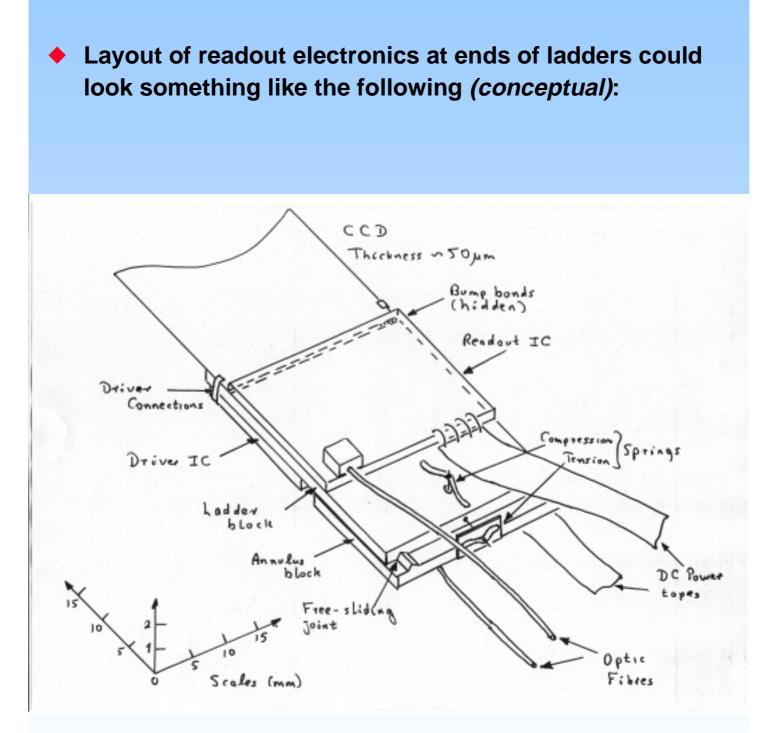
- Total power dissipation/CCD ~3.6 W (1 V p-p clocks)
- N.B. Freezing clocking between TESLA bunch trains reduces power dissipation by a further factor of 200
- For layer 1 of the VXD mean P_D <150 mW
- ◆ CCDs in outer layers can be clocked at a lower frequency (*much smaller backgrounds*) — → Total VXD power dissipation ~few watts
- Further simulation work needed (ISE TCAD)

Column-parallel CCD signal-handling

- Simplify reset circuit passive with resistive load
- Signal-processing (digitisation, real-time cluster-finding) performed adjacent to CCD — in local readout chip
- 1-d row of staggered bump bonds (industry-standard) interconnects CCD and readout chip — 60 μm pitch
- Sparsified data transmitted off detector by optical fibre(s)

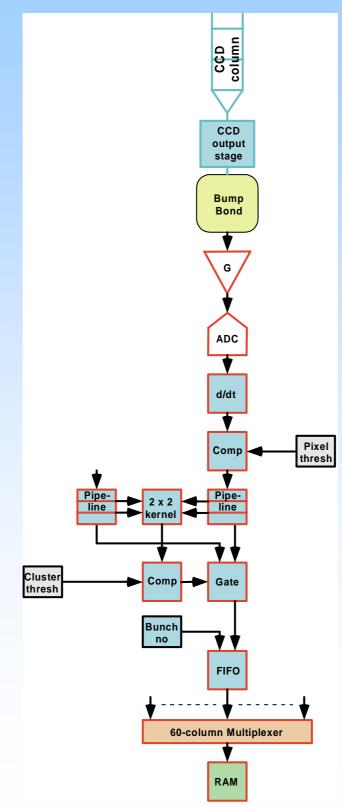


Column-parallel CCD signal-handling



Column-parallel CCD signal-handling

Functionality of readout chip (n.b. very preliminary ideas — more study needed):



Column-parallel CCD data rates

- Proposal is to read out the CCDs throughout the 950 μs bunch train, storing *sparsified* cluster data in local RAM
 - Based on current background rate estimates for TESLA, we would expect the following (per bunch train):

<u>Layer</u>	<u>CCD mm²</u>	Ladders/CCDs	<u>Clk/T_{RO}</u>	Hits/mm ²	<u>Σ backgrnd</u>
1	100x13	8/8	50MHz/50μs	5.9	1165 K
2	125x22	8/16	25MHz/250μs	2.9	484 K
3	125x22	12/24	25MHz/250μs	1.1	276 K
4	125x22	16/32	25MHz/250μs	0.9	301 K
5	125x22	20/40	25MHz/250 μs	0.6	251 K

- Total no of hits to store during bunch-train ~2.5 x 10⁶
- Each hit can contain up to 4 pixels (2 x 2 clusters) and must also be address-tagged → 6 bytes/hit
- Data volume to store during bunch-train ~15 Mbytes
- On receipt of a trigger, only data corresponding to 1 subsequent frame from each CCD need to be retained, so data volume to be transferred off the detector before next bunch-train is reduced to ~2.1 Mbytes per event
- For a trigger rate <50 Hz (!), data to transmit off detector
 ~21 Mbytes per bunch-train → 1 optical fibre per end!
- N.B. If data storage cannot be on-detector, <u>all</u> sparsified data must be exported → 1 – 4 optical fibres per CCD

Conclusions



- Initial results just emerging are very encouraging:
 - Substrate-free mechanics appears viable
 - Simulations show that clocking a column-parallel structure at 50 MHz is feasible — waveform integrity and power are both acceptable
- The column-parallel architecture makes CCDs fullycompatible with the TESLA environment
- There are new ideas for in-detector signal processing, data sparsification and post-trigger processing
- CCD radiation damage studies are being prepared
- A close involvement with CCD designers/manufacturers is maintained, and is crucial